

A Versatile Crack Inspection Portable System based on Classifier Ensemble and Controlled Illumination



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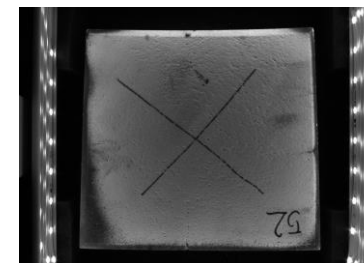
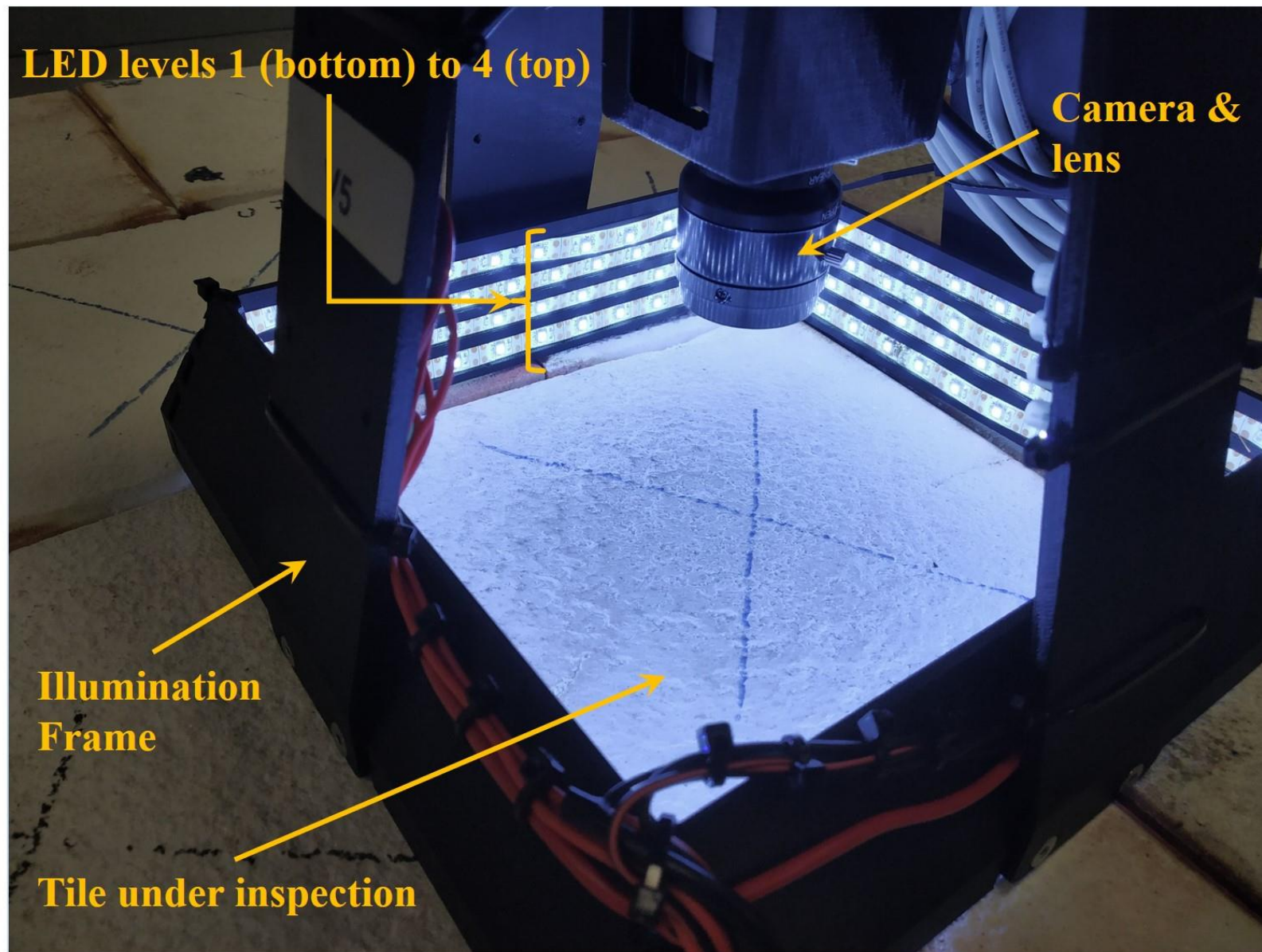
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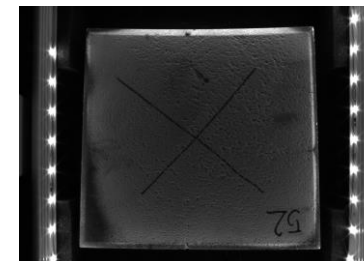
⁵Dipartimento di Ingegneria Navale, Elettrica, Elettronica e della Telecomunicazioni, University of Genova, Italy

Paper Highlights

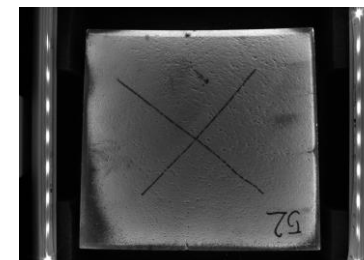
- A novel setup for automatic visual inspection of cracks in ceramic tile
 - Designed for field work with constraints in its maximum dimensions
- Studies the effect of various classifiers and height-varying illumination
 - Classifiers trained on customized as well as state-of-the-art architectures
 - Performance evaluation at patch as well as image-level
- Insights about illumination
 - Which illumination configuration can help in a challenging real-world industrial environment



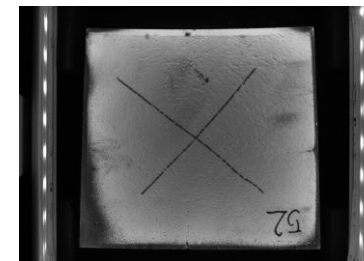
All lights



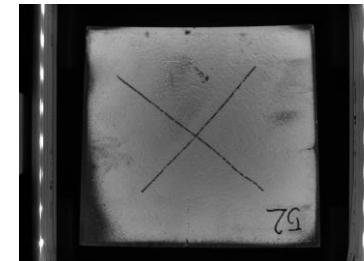
Lights at level 1



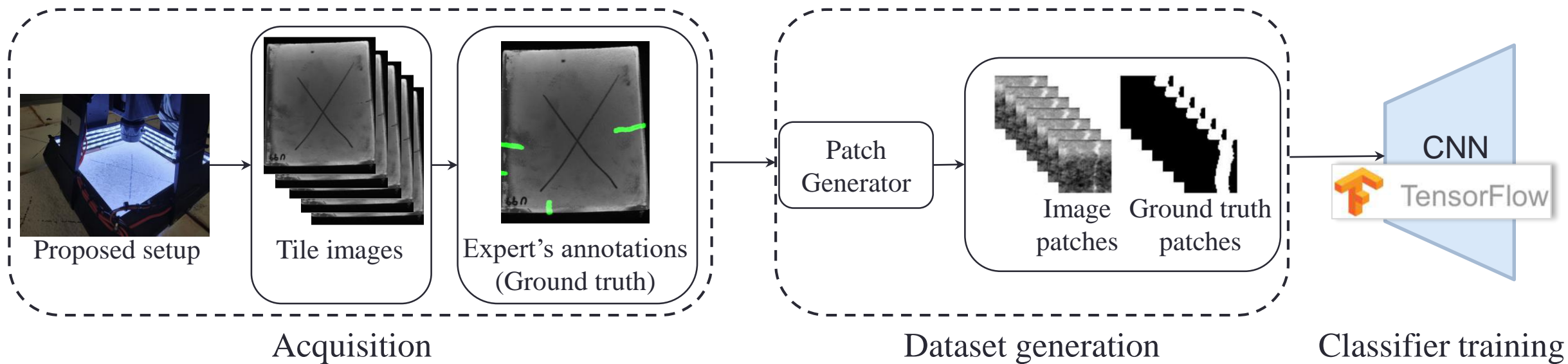
Lights at level 2



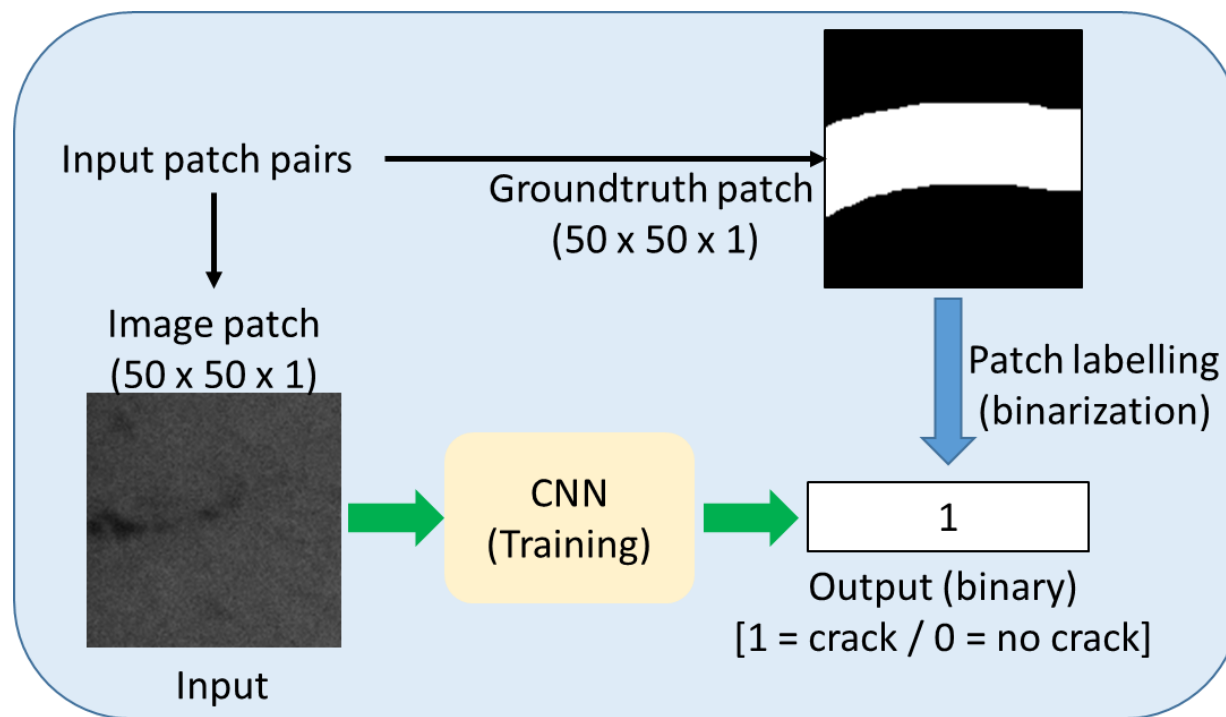
Lights at level 3



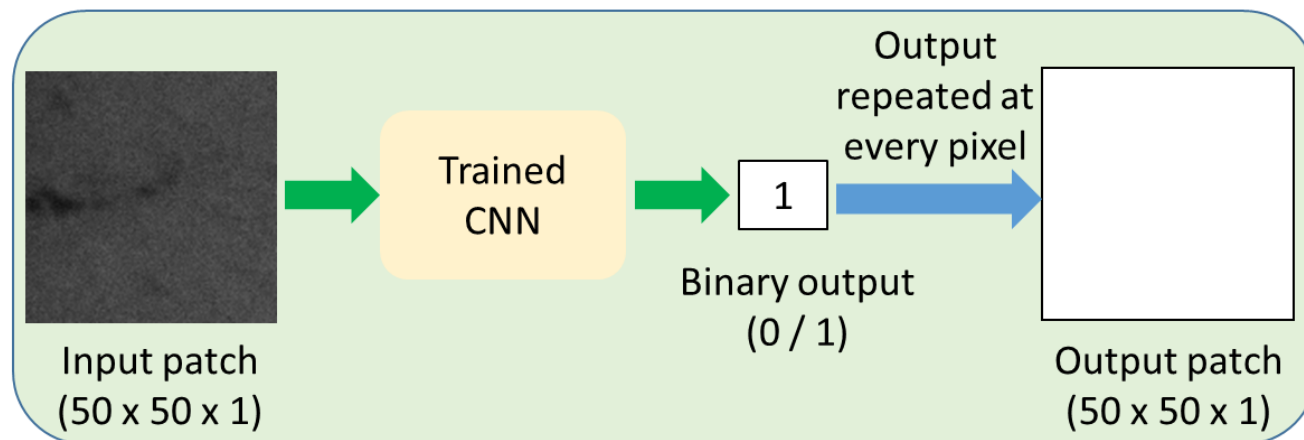
Lights at level 4



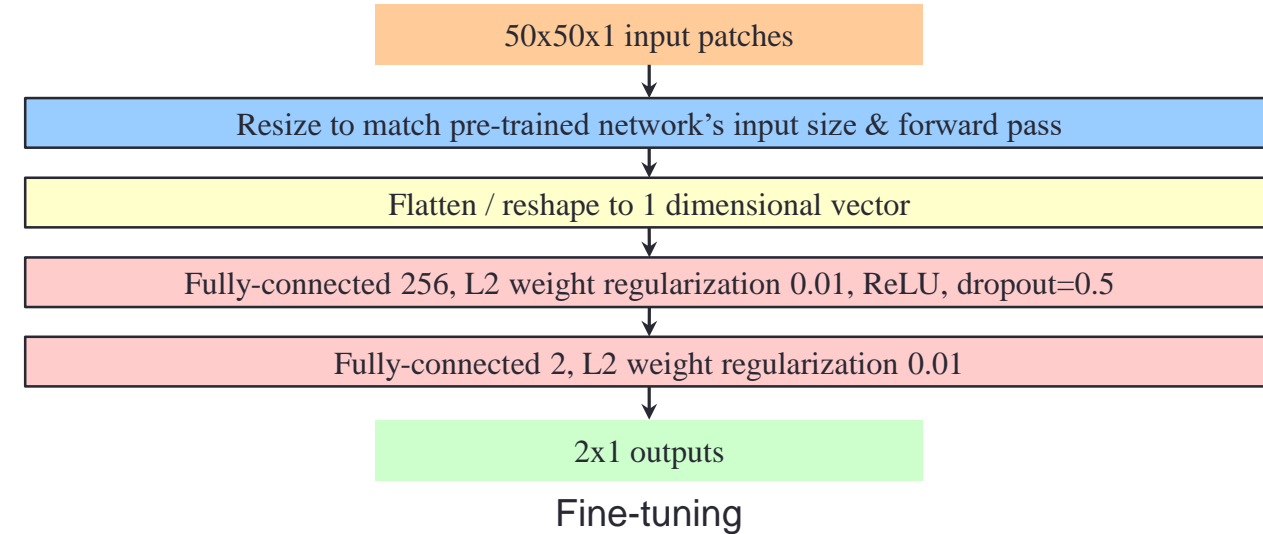
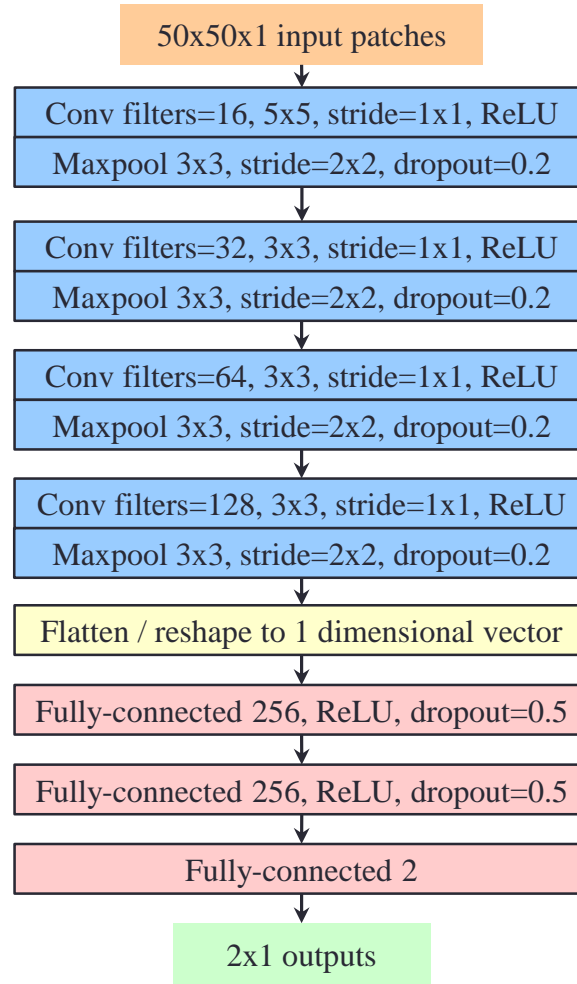
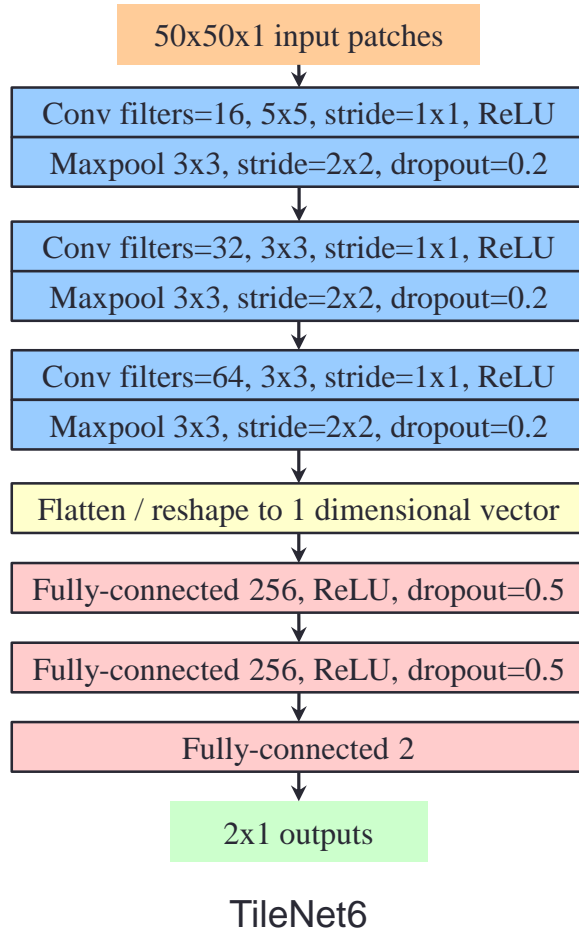
Training



Inference



Architectures



Architectures used for fine-tuning:

- **VGG16** (Simonyan and A. Zisserman, ICLR 2015)
- **ResNet50** (He et al., CVPR 2016)
- **DenseNet121** (Huang et al., CVPR 2017)
- **InceptionResNet-v2** (Szegedy et al., AAAI 2017)
- **NASNetLarge** (Zoph et al., CVPR 2018 Spotlight)
- **Xception** (Chollet, CVPR 2017)

Patch-level Metrics

- Accuracy

$$\frac{TP + TN}{TP + FP + FN + TN}$$

- Matthew's Correlation Coefficient

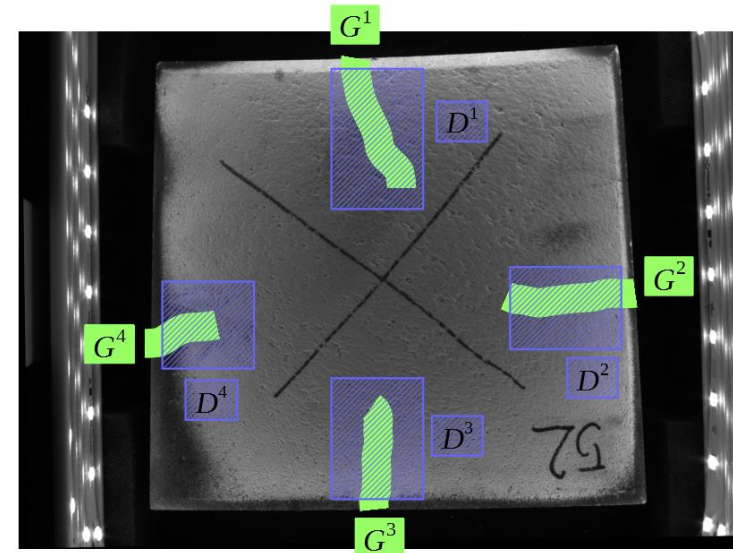
$$MCC = \frac{TP * TN - FP * FN}{\sqrt{(TP + FP)(TP + FN)(TN + FP)(TN + FN)}}$$

G : Set of cracks (closed contours or connected components) in ground truth

D : Set of detected cracks (closed contours or connected components) in the given image

$n(X)$: Number of elements in set X , (X represents $D; G$ or any other set of cracks)

$I(\bullet)$: Indicator function, $I(True) = 1$; $I(False) = 0$



$$G \cap D = \{(G^1, D^1), (G^2, D^2), (G^3, D^3), (G^4, D^4)\}$$

Image-level Metrics

- Crack Presence Accuracy

$$CPA = average(PM) = \frac{1}{N} \sum_{t=1}^N (PM)_t \quad \text{where} \quad (PM)_t = I(I(n(G_t) > 0) == I(n(D_t) > 0))$$

- Crack Count F1 Score

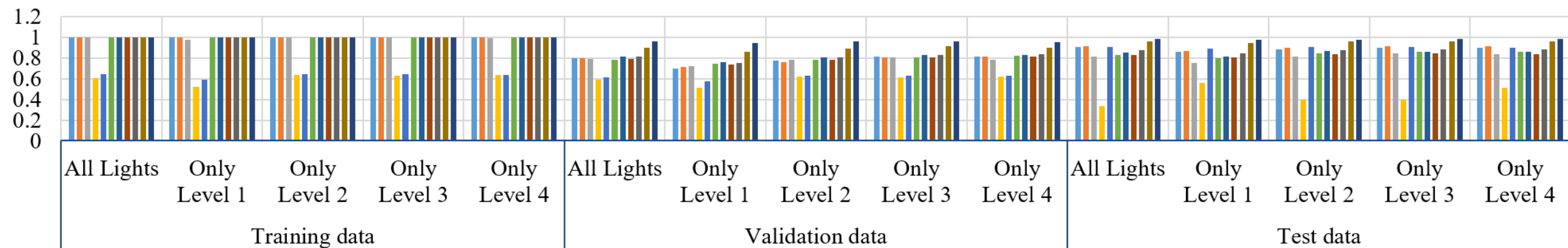
$$CCF1 = \frac{\sum_{t=1}^N F1_t * a_t}{\sum_{t=1}^N a_t}, \quad \text{where } a_t = n(G_t) + 1$$

$$F1_t = 2 * \frac{P_t * R_t}{P_t + R_t}$$

$$\text{Precision } (P_t) = \begin{cases} \frac{n(G_t \cap D_t)}{n(D_t)}, & \text{if } n(D_t) > 0, \\ 1, & \text{otherwise,} \end{cases}$$

$$\text{Recall } (R_t) = \begin{cases} \frac{n(G_t \cap D_t)}{n(G_t)}, & \text{if } n(G_t) > 0, \\ 1, & \text{otherwise,} \end{cases}$$

Accuracy

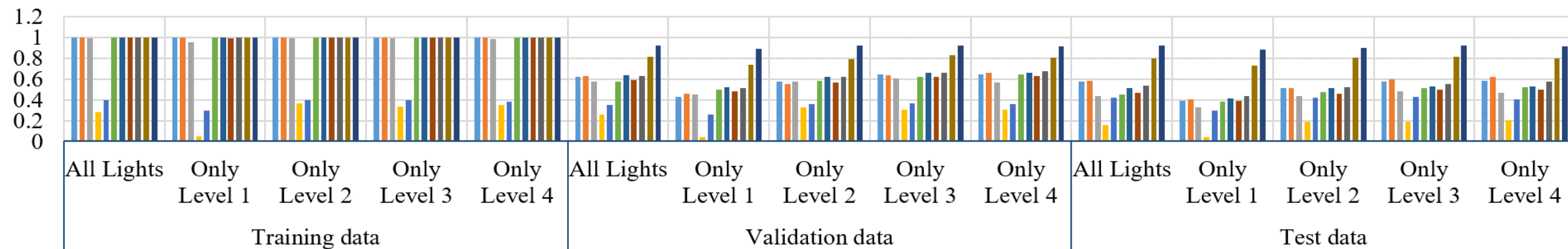


TileNet6
ResNet50 -features
InceptionResNet-v2 features
Xception-finetune_all

TileNet7
ResNet50-finetune_conv_5x_onwards
NASNetLarge features
Xception-finetune_all_HR

VGG16 features
DenseNet121 features
Xception features

MCC

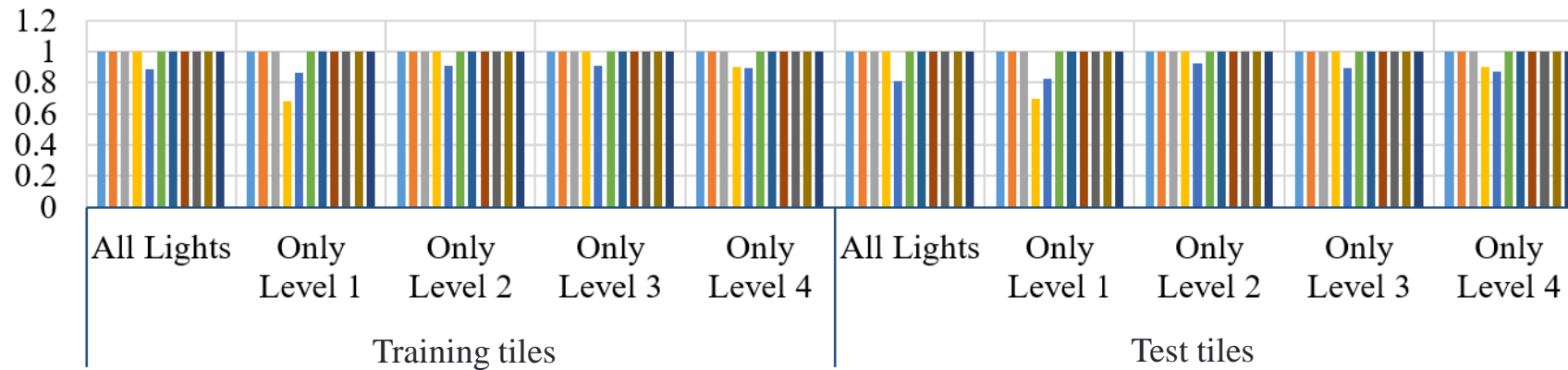


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Crack Presence Accuracy

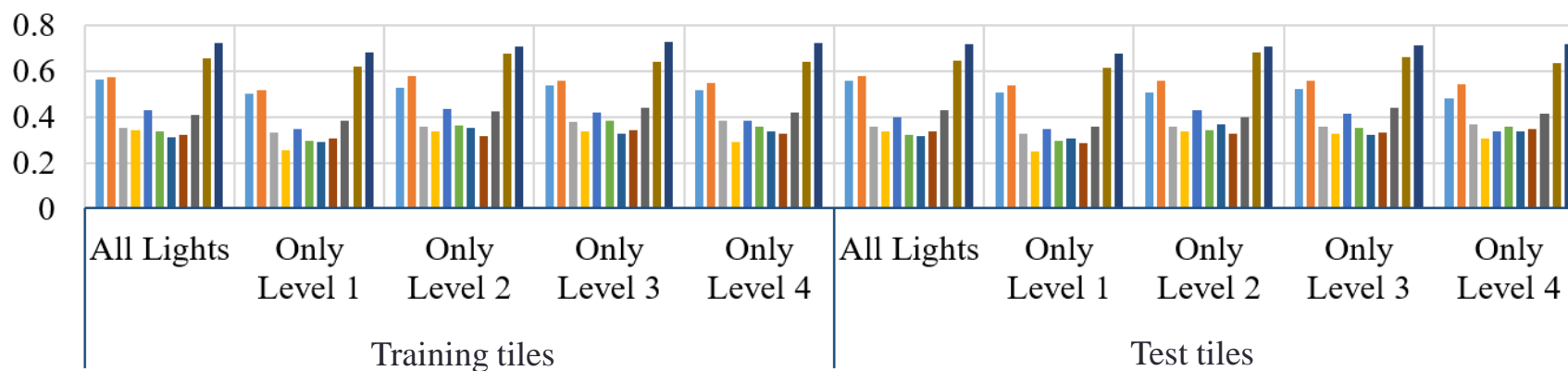


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Crack Count F1 Score

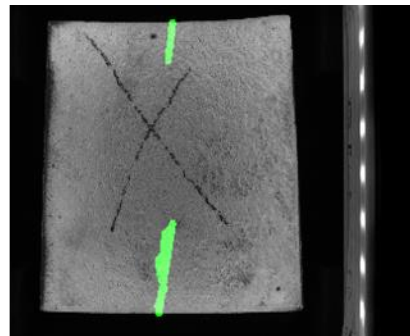


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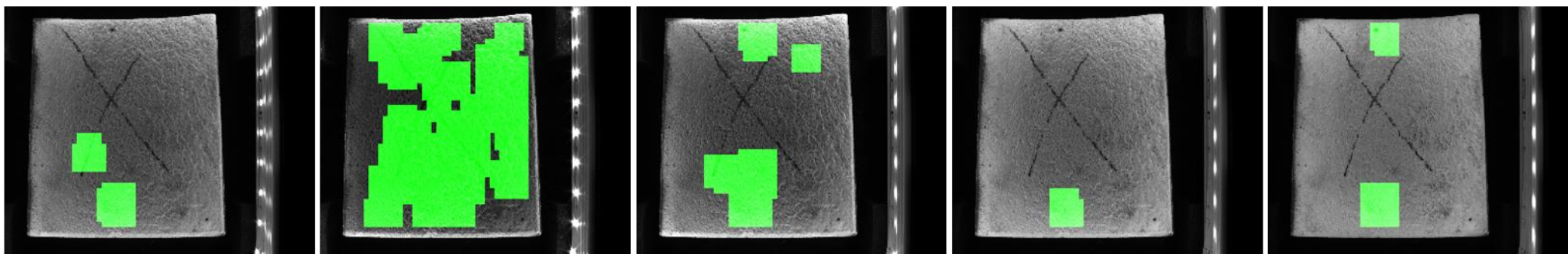
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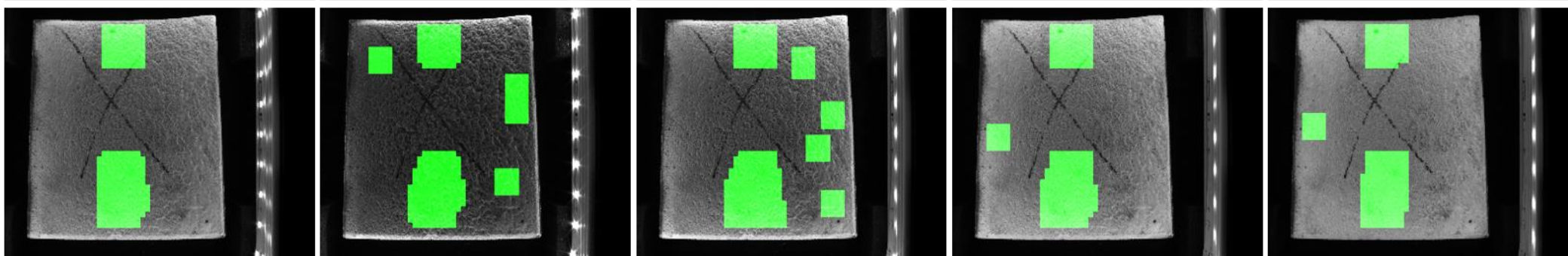
Ground truth



Low-resolution



High-resolution



All lights

Only Level 1

Only Level 2

Only Level 3

Only Level 4

Conclusions

■ Lights

- All lights configuration provides the best results
- Lights placed at greater heights more effective than those placed near the tile's surface

■ Architecture

- Increasing depth of the network improves the results
- Fine-tuning pre-trained weights of the Xception architecture provided the best results

■ Spatial resolution

- Use of high-resolution patches improves the results compared to low-resolution
- Study should help in deciding the resolution versus performance trade-off for field use